Structural and Transport Properties of Fully Epitaxial Grown Fe/MgO/InAs for Electrical Spin Injections

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Fe/MgO/InAs junction has a significant adventage compared to Fe/MgO/GaAs due to a higher electron mobility and larger spin-orbit interaction for spintronics device applications. Furthermore, spin coherent tunneling is expected to result from the high quality of an epitaxial MgO tunnel barrier. In this experiment, we first obtained the growth of single crystal MgO layers on InAs substrates. Using by a cluster molecular beam epitaxy (MBE) all the sequential layers of Fe, MgO, and InAs buffer layer were in-situ grown on (2 × 4) reconstructed InAs (001) substrates without vacuum break. Reflection high-energy electron diffraction (RHEED) patterns in fig. 1 indicates that the MgO grown at room temperature is polycrystalline while ones grown at higher temperature (100-400°C) are single crystalline. In addition, it is clearly shown that polycrystalline component disapprears as the growth temerature increases. Fe layer grown at 200°C exhibits polycrystalline dominant only on top of MgO at room temperatures as a function of the growth temperature. High resolution transmission electron microscopy (HRTEM) clearly demostrates the crystallinities of Fe/MgO/InAs heterostructures.

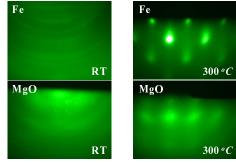


Fig. 1. RHEED patterns of the MgO(below) and Fe(above) along the [100] azimuths of the InAs(001) substrate. Growth temperatures during MgO deposition are RT(left) and 300°C (right).

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The Electrical Transport Properties of La_{0.7-x}Nd_xPb_{0.3}MnO₃ Compounds

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The electrical transport properties of the La_{0.7.x}Nd_xPb_{0.3}MnO₃ ($0.0 \le x \le 0.7$) have been systematically studied from both the experimental and theoretical viewpoints. The temperature dependence of the resistivity was found the metal insulator transition (MIT) at the transition temperature, T_{P_r} , between 56-331 K (depend on x). On the metallic side the low temperature conductivity varies as a power law contributions, $\rho=\rho_0+\rho_2T^+\rho_{52}T^{5/2}$, due to the effects of electron-electron interaction and electron-magnon scattering [1]. On the insulating side of the transition the resistivity will be good fitted using the equation $\rho(T)=\rho_n \exp[(T_0/T)^n]$, n=1/4 and n=1/2, for sample x=0.5 and 0.7 at different temperature ranges. The reasonable T_0 values indicated the variable range hopping (VRH) with the presence of the Coulomb interactions in these compounds. At intermediate temperatures from the competition between the metallic conduction mechanism and the VRH conduction regime [3]. To study the transition behavior we employ a numerical simulations on random resistor networks. These numerical results are in good agreement with experimental measurements.

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